

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
		Examiner John L. Goodrow	Art Unit 1756	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0142264	07-2004	Tanaka et al.	430/108.4
*	B	US-2003/0165760	09-2003	Higuchi et al.	430/108.4
*	C	US-2003/0129518	07-2003	Sawada et al.	430/109.4
*	D	US-2003/0219670	11-2003	Sawada et al.	430/109.4
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	I	US-			
	J	US-			
	K	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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